



TEST REPORT

Reference No...... : WTX24X07174094E
Applicant : GlobTek, Inc.
Address : 186 Veterans Dr. Northvale, NJ 07647 USA
Manufacturer : 1.GlobTek, Inc.
2.GlobTek (Suzhou) Co.,Ltd
1.186 Veterans Dr. Northvale.NJ07647 USA
Address : 2. Building 4, No.76,Jin Ling East Rd.,Suzhou Industrial Park, Suzhou,
JiangSu 215021, China
Product Name : MEDICAL AC/DC ADAPTOR
Model No...... : GTM3T41-12-150R-3
Standards : EN 60601-1-2:2015+A1:2021
Date of Receipt sample : 2024-08-01
Date of Test..... : 2024-08-01 to 2024-08-07
Date of Issue : 2024-08-07
Test Report Form No. : WTX_EN 60601_1_2_2015_B
Test Result..... : Pass

Remarks:

The results shown in this test report refer only to the sample(s) tested, this test report cannot be reproduced, except in full, without prior written permission of the company. The report would be invalid without specific stamp of test institute and the signatures of approver.

Prepared By:

Waltek Testing Group (Shenzhen) Co., Ltd.

Address: 1/F., Room 101, Building C, Hengwei Industrial Park, Liuxian 2nd Road,
Block 70 Bao'an District, Shenzhen, Guangdong, China

Tel.: +86-755-33663308 Fax.: +86-755-33663309 Email: sem@waltek.com.cn

Tested by:

Toby Zhang

Approved by:

Evan Cai



TABLE OF CONTENTS

1. GENERAL INFORMATION	5
1.1 PRODUCT DESCRIPTION FOR EQUIPMENT UNDER TEST (EUT)	5
1.2 TEST STANDARDS.....	6
1.3 TEST METHODOLOGY	6
1.4 EUT SETUP AND OPERATION MODE	7
1.5 PERFORMANCE CRITERIA FOR EMS.....	7
1.6 TEST EQUIPMENT LIST AND DETAILS	8
2. SUMMARY OF TEST RESULTS.....	11
3. CONDUCTED EMISSION.....	12
3.1 MEASUREMENT UNCERTAINTY	12
3.2 BASIC TEST SETUP BLOCK DIAGRAM	12
3.3 ENVIRONMENTAL CONDITIONS	12
3.4 SUMMARY OF TEST RESULTS.....	12
4. RADIATED EMISSION.....	15
4.1 MEASUREMENT UNCERTAINTY	15
4.2 BASIC TEST SETUP BLOCK DIAGRAM	15
4.3 CORRECTED AMPLITUDE & MARGIN CALCULATION.....	16
4.4 ENVIRONMENTAL CONDITIONS	16
4.5 SUMMARY OF TEST RESULTS.....	16
5. HARMONIC CURRENT EMISSIONS	19
5.1 TEST PROCEDURE	19
5.2 TEST STANDARDS.....	19
5.3 ENVIRONMENTAL CONDITIONS	19
5.4 BASIC TEST SETUP BLOCK DIAGRAM	19
5.5 HARMONIC CURRENT EMISSIONS TEST DATA.....	19
6. VOLTAGE FLUCTUATION FLICKER.....	20
6.1 TEST PROCEDURE	20
6.2 TEST STANDARDS.....	20
6.3 ENVIRONMENTAL CONDITIONS	20
6.4 BASIC TEST SETUP BLOCK DIAGRAM	20
6.5 VOLTAGE FLUCTUATION AND FLICKER TEST DATA.....	20
7. ELECTROSTATIC DISCHARGES (ESD).....	22
7.1 TEST PROCEDURE	22
7.2 TEST PERFORMANCE.....	22
7.3 ENVIRONMENTAL CONDITIONS	22
7.4 BASIC TEST SETUP BLOCK DIAGRAM	22
7.5 ELECTROSTATIC DISCHARGE IMMUNITY TEST DATA.....	23
8. CONTINUOUS RF ELECTROMAGNETIC FIELD DISTURBANCES (RS).....	24
8.1 TEST PROCEDURE	24
8.2 TEST PERFORMANCE.....	24
8.3 ENVIRONMENTAL CONDITIONS	24
8.4 BASIC TEST SETUP BLOCK DIAGRAM	24
8.5 CONTINUOUS RADIATED DISTURBANCES TEST DATA.....	25
9. ELECTRICAL FAST TRANSIENTS (EFT)	26
9.1 TEST PROCEDURE	26
9.2 TEST PERFORMANCE.....	26
9.3 ENVIRONMENTAL CONDITIONS	26
9.4 BASIC TEST SETUP BLOCK DIAGRAM	26
9.5 ELECTRICAL FAST TRANSIENTS TEST DATA.....	27
10. SURGES.....	28
10.1 TEST PROCEDURE	28
10.2 TEST PERFORMANCE	28



Reference No.: WTX24X07174094E

10.3 ENVIRONMENTAL CONDITIONS	28
10.4 BASIC TEST SETUP BLOCK DIAGRAM	28
10.5 SURGE TEST DATA	29
11. CONTINUOUS INDUCED RF DISTURBANCES (C/S)	30
11.1 TEST PROCEDURE	30
11.2 TEST PERFORMANCE	30
11.3 ENVIRONMENTAL CONDITIONS	30
11.4 BASIC TEST SETUP BLOCK DIAGRAM	30
11.5 CONTINUOUS CONDUCTED DISTURBANCES TEST DATA	31
12. POWER-FREQUENCY MAGNETIC FIELDS (PFMF)	32
12.1 TEST PROCEDURE	32
12.2 TEST PERFORMANCE	32
12.3 ENVIRONMENTAL CONDITIONS	32
12.4 BASIC TEST SETUP BLOCK DIAGRAM	32
12.5 POWER-FREQUENCY MAGNETIC FIELD TEST DATA	32
13. VOLTAGE DIPS AND INTERRUPTIONS	33
13.1 TEST PROCEDURE	33
13.2 TEST PERFORMANCE	33
13.3 ENVIRONMENTAL CONDITIONS	33
13.4 BASIC TEST SETUP BLOCK DIAGRAM	33
13.5 VOLTAGE DIPS AND INTERRUPTIONS TEST DATA	34
EXHIBIT 1 - PRODUCT LABELING	35
PROPOSED CE LABEL FORMAT	35
PROPOSED LABEL LOCATION ON EUT	35
EXHIBIT 2 - EUT PHOTOGRAPHS	36
EXHIBIT 3 - TEST SETUP PHOTOGRAPHS	43

WALTEK



Report version

Version No.	Date of issue	Description
Rev.00	2024-08-07	Original
/	/	/

WALTEK



1. GENERAL INFORMATION

1.1 Product Description for Equipment Under Test (EUT)

General Description of EUT	
Product Name:	MEDICAL AC/DC ADAPTOR
Trade Name:	 GlobTek, Inc.
Model No.:	GTM3T41-12-150R-3
Adding Model(s):	/
<i>Note: The test data is gathered from a production sample, provided by the manufacturer.</i>	

Technical Characteristics of EUT	
Rated Voltage:	Input: 230V 50Hz34mA Output: 12V--150mA
Rated Current:	/
Rated Power:	/
Power Adaptor Model:	/
Highest Internal Frequency:	Below 108MHz
Classification of Equipment:	Class B



1.2 Test Standards

The tests were performed according to following standards:

EN 60601-1-2:2015+A1:2021: Medical electrical equipment – Part 1-2: General requirements for basic safety and essential performance – Collateral standard: Electromagnetic compatibility – Requirements and tests.

Maintenance of compliance is the responsibility of the manufacturer. Any modification of the product maybe which result in lowering the emission/immunity should be checked to ensure compliance has been maintained.

1.3 Test Methodology

All measurements contained in this report were conducted with the standards IEC 60601-1-2 for Medical electrical equipment – Part 1-2: General requirements for basic safety and essential performance – Collateral standard: Electromagnetic compatibility – Requirements and tests.

WALTEK



1.4 EUT Setup and Operation Mode

The equipment under test (EUT) was configured to measure its highest possible emission/immunity level. The test modes were adapted according to the operation manual for use, more detailed description as follows:

Test Mode List			
Test Mode	Description	Remark	Power Supply Mode
TM1	Working mode	Model: GTM3T41-150-R-12(12V/150mA)	AC 230V/50Hz

EUT Cable List and Details				
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite	With / Without Chip
DC cable	1.89	Unshielded	Without	Without

Special Cable List and Details				
Cable Description	Length (m)	Shielded/Unshielded	With / Without Ferrite	With / Without Chip
/	/	/	/	/

Auxiliary Equipment List and Details			
Description	Manufacturer	Model	Serial Number
Cement load	/	/	/

1.5 Performance Criteria for EMS

All the test data has been collected, reduced, and analyzed within this report in accordance with Immunity requires the following as specific performance criteria:

- A. The apparatus shall continue to operate as intended during and after the test. The manufacturer specifies some minimum performance level. The performance level may be specified by the manufacturer as a permissible loss of performance.
- B. The apparatus shall continue to operate as intended after the test. This indicates that the EUT does not need to function at normal performance levels during the test, but must recover. Again some minimal performance is defined by the manufacturer. No change in operating state or loss of data is permitted.
- C. Temporary loss of function is allowed. Operation of the EUT may stop as long as it is either automatically reset or can be manually restored by operation of the controls.



1.6 Test Equipment List and Details

Description	Manufacturer	Model	Serial No.	Cal. Date	Due. Date
☐ Chamber A: Below 1GHz					
Spectrum Analyzer	Rohde & Schwarz	FSP30	836079/035	2024-02-24	2025-02-23
EMI Test Receiver	Rohde & Schwarz	ESPI	101611	2024-03-19	2025-03-18
Trilog Broadband Antenna	Schwarz beck	VULB9163	9163-333	2023-03-20	2026-03-19
Loop Antenna	Schwarz beck	FMZB 1516	9773	2024-02-26	2025-02-25
Amplifier	HP	8447F	2805A03475	2024-02-24	2025-02-23
EMI Test Software (Radiated Emission A)	Farad	EZ-EMC	RA-03A1 (1.1.4.2)	/	/
☐ Chamber A: Above 1GHz					
Amplifier	C&D	PAP-1G18	2002	2024-02-27	2025-02-26
Horn Antenna	ETS	3117	00086197	2024-02-26	2025-02-25
Spectrum Analyzer	Rohde & Schwarz	FSP30	836079/035	2024-02-24	2025-02-23
EMI Test Software (Radiated Emission A)	Farad	EZ-EMC	RA-03A1 (1.1.4.2)	/	/
☒ Chamber B: Below 1GHz					
Trilog Broadband Antenna	Schwarz beck	VULB9163(B)	9163-635	2024-03-17	2027-03-16
Amplifier	Agilent	8447D	2944A10457	2024-02-24	2025-02-23
EMI Test Receiver	Rohde & Schwarz	ESPI	101391	2024-02-24	2025-02-23
EMI Test Software (Radiated Emission B)	Farad	EZ-EMC	RA-03A1 (1.1.4.2)	/	/
☐ Chamber C: Below 1GHz					
EMI Test Receiver	Rohde & Schwarz	ESIB 26	100401	2024-02-27	2025-02-26
Trilog Broadband Antenna	Schwarz beck	VULB 9168	1194	2024-04-18	2027-04-17
Amplifier	HP	8447F	2944A03869	2024-02-24	2025-02-23
EMI Test Software (Radiated Emission C)	Farad	EZ-EMC	RA-03A1-2 (1.1.4.2)	/	/
☐ Chamber C: Above 1GHz					
Horn Antenna	POAM	RTF-118A	1820	2023-03-10	2026-03-09
Amplifier	Tonscend	TAP01018050	AP22E806235	2024-02-27	2025-02-26
EMI Test Receiver	Rohde & Schwarz	ESIB 26	100401	2024-02-27	2025-02-26
EMI Test Software (Radiated Emission C)	Farad	EZ-EMC	RA-03A1-2 (1.1.4.2)	/	/



☒ Conducted Room 1#					
EMI Test Receiver	Rohde & Schwarz	ESCI	100525	2023-12-12	2024-12-11
Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100911	2024-02-24	2025-02-23
AC LISN	Schwarz beck	NSLK8126	8126-279	2024-02-24	2025-02-23
EMI Test Software (Conducted Emission Room 1#)	Farad	EZ-EMC	3A1*CE-RE 1.1.4.3	/	/
☐ Conducted Room 2#					
EMI Test Receiver	Rohde & Schwarz	ESPI	101259	2024-02-24	2025-02-23
LISN	Rohde & Schwarz	ENV 216	100097	2024-02-24	2025-02-23
EMI Test Software (Conducted Emission Room 2#)	SKET	EMC-I	1.3.0.2	/	/
☒ Harmonics &Flicker					
Digital Power Analyzer	California Instrument	CTS	72831	2024-02-24	2025-02-23
Power Source	California Instrument	5001IX-CTS-400	60077	2024-02-24	2025-02-23
Test Software (Harmonics &Flicker)	AMETEK	CTS4	4.30	/	/
☒ Electrostatic discharges					
ESD Generator	LIONCEL	ESD-203B	0170901	2024-02-26	2025-02-25
☒ Power-frequency magnetic field (PFMF)					
PMF Generator	LIONCEL	PMF-801C-C	0171101	2024-02-24	2025-02-23
PMF Antenna	LIONCEL	PMF-801C-A	0180302	2024-02-24	2025-02-23
Instantaneous PMF Generator Module	LIONCEL	PMF-801C-T	0171001	2024-02-24	2025-02-23
☒ Electronic fast transient(EFT)/Surges/Dips					
Transient 2000	EMC PARTNER	TRA2000	836	2024-03-19	2025-03-18
Couple Clamp	EMC PARTNER	CN-EFT1000	513	2024-03-19	2025-03-18
☒ Radio frequency, continuous conducted (C/S)					
CONDUCTED IMMUNITY TEST SYSTEM	FRANKONIA	CIT-10/75	126B1247/2013	2024-02-27	2025-02-26
Attenuator	EMTEST	MA-5100/6BF2	1009	2024-02-27	2025-02-26
CDN	Luthi	L-801M2/M3	2665	2024-02-27	2025-02-26
CDN	LIONCEL	CDN-T8	0210401	2024-02-24	2025-02-23
EM Clamp	TESEQ	KEMZ801A	45028	2024-02-26	2025-02-25
Test Software (Radio frequency, Continuous	SKET	EMC-S	V1.4.0.16	/	/



conducted)					
☒ Radio frequency electromagnetic Field (R/S)					
Signal Generator	HP	8665B	3438A00604	2024-02-27	2025-02-26
Power Sensor	Agilent	E9301A	MY52450001	2024-02-27	2025-02-26
Power Sensor	Agilent	E9304A	MY55081055	2024-02-27	2025-02-26
RF Power Amplifier	MicoTop	MPA-80-1000-25 0	MPA1906239	2024-02-27	2025-02-26
RF Power Amplifier	MicoTop	MPA-1000-6000- 100	MPA1906238	2024-02-27	2025-02-26
Antenna	SCHWARZBECK	STLP 9129	9129 114	/	/
Power Meter	Agilent	E4419B	GB42420578	2024-02-27	2025-02-26
Test Software (Radio frequency electromagnetic Field)	EMtrace	EM3	V1.2.6.2	/	/

WALTEK



2. SUMMARY OF TEST RESULTS

Standards	Description of Test Item	Result
EN 60601-1-2	Conducted Disturbance CISPR 11 Class B	Compliant
	Radiated Disturbance CISPR 11 Class B	Compliant
	Harmonic Current Emission IEC 61000-3-2	Compliant
	Voltage Fluctuation and Flicker IEC 61000-3-3	Compliant
	Electrostatic Discharge Immunity in accordance with IEC 61000-4-2	Compliant
	Continuous Radiated Disturbances Immunity in accordance with IEC 61000-4-3	Compliant
	Electrical Fast Transient/Burst Immunity in accordance With IEC 61000-4-4	Compliant
	Surges Immunity in accordance with IEC 61000-4-5	Compliant
	Continuous Conducted Disturbances Immunity in accordance with IEC 61000-4-6	Compliant
	Power-frequency Magnetic Fields Immunity in accordance with IEC 61000-4-8	Compliant
	Voltage Dips/Interruptions Immunity in accordance with IEC 61000-4-11	Compliant



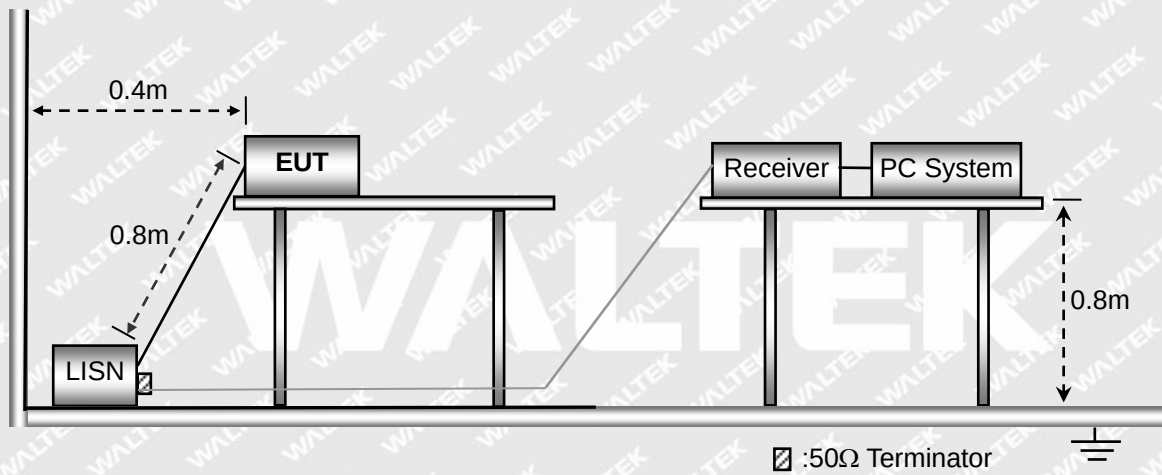
3. Conducted Emission

3.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement:

Measurement uncertainty		
Parameter	Conditions	Uncertainty
Conducted Emissions	Conducted	9-150kHz ±3.74dB
		0.15-30MHz ±3.34dB

3.2 Basic Test Setup Block Diagram



3.3 Environmental Conditions

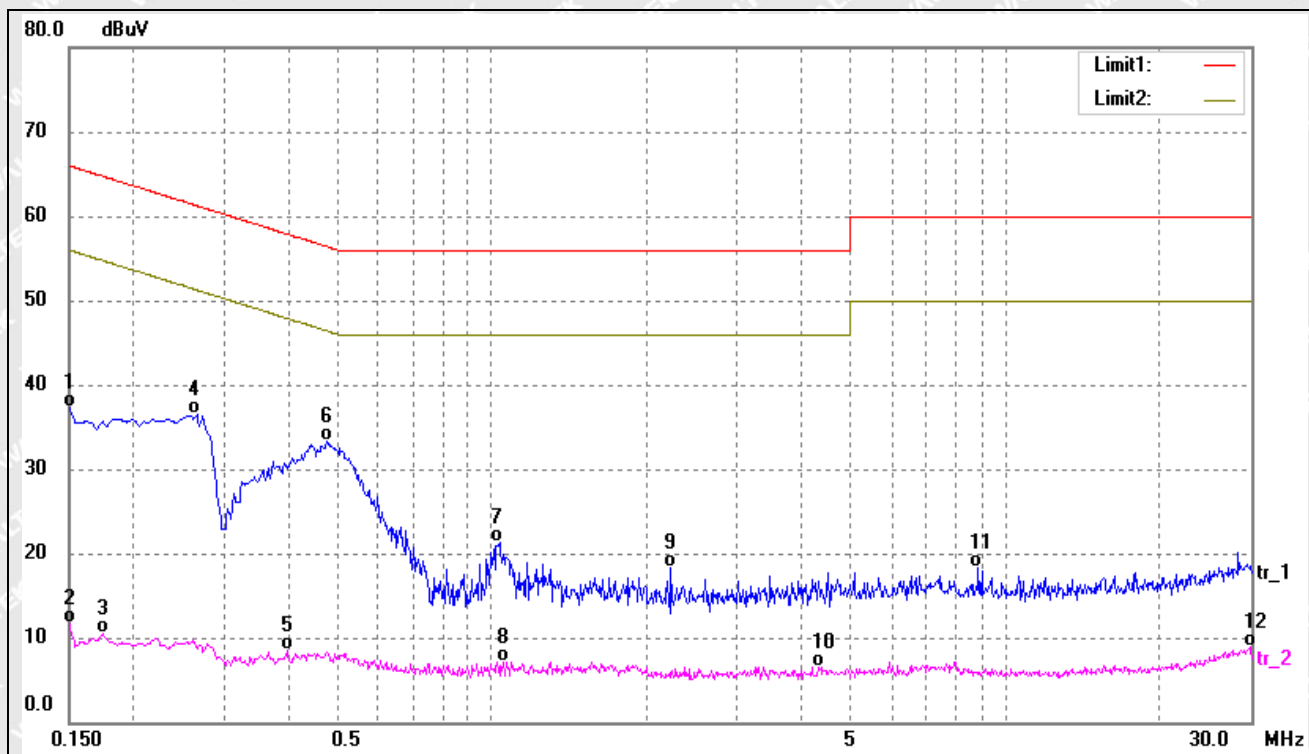
Temperature:	23.5 °C
Relative Humidity:	54 %
ATM Pressure:	998 mbar

3.4 Summary of Test Results

Please find the results below:



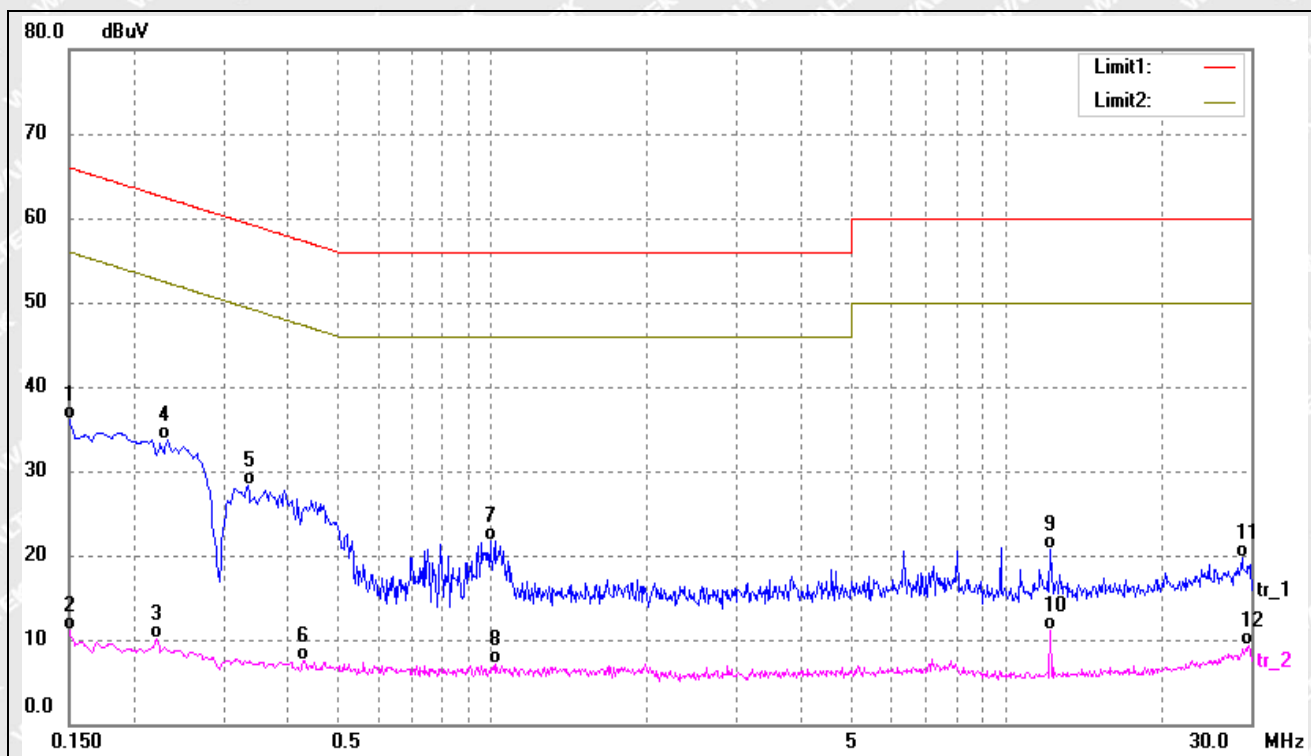
Test mode:	TM1	Polarity:	Line
------------	-----	-----------	------



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1	0.1500	27.40	9.97	37.37	65.99	-28.62	QP
2	0.1500	1.66	9.97	11.63	55.99	-44.36	AVG
3	0.1740	0.51	9.96	10.47	54.76	-44.29	AVG
4	0.2660	26.47	9.95	36.42	61.24	-24.82	QP
5	0.3980	-1.42	9.95	8.53	47.89	-39.36	AVG
6*	0.4780	23.41	9.95	33.36	56.37	-23.01	QP
7	1.0339	11.39	9.97	21.36	56.00	-34.64	QP
8	1.0540	-2.86	9.97	7.11	46.00	-38.89	AVG
9	2.2260	8.22	10.01	18.23	56.00	-37.77	QP
10	4.3340	-3.58	10.08	6.50	46.00	-39.50	AVG
11	8.8500	7.94	10.31	18.25	60.00	-41.75	QP
12	29.9740	-3.23	12.18	8.95	50.00	-41.05	AVG



Test mode:	TM1	Polarity:	Neutral
------------	-----	-----------	---------



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB)	Result (dBuV)	Limit (dBuV)	Margin (dB)	Detector
1	0.1499	26.17	9.97	36.14	66.00	-29.86	QP
2	0.1499	1.08	9.97	11.05	56.00	-44.95	AVG
3	0.2220	0.13	9.94	10.07	52.74	-42.67	AVG
4*	0.2340	23.76	9.94	33.70	62.30	-28.60	QP
5	0.3340	18.38	9.95	28.33	59.35	-31.02	QP
6	0.4300	-2.44	9.95	7.51	47.25	-39.74	AVG
7	0.9940	11.70	9.97	21.67	56.00	-34.33	QP
8	1.0180	-2.92	9.97	7.05	46.00	-38.95	AVG
9	12.2139	10.10	10.55	20.65	60.00	-39.35	QP
10	12.2139	0.57	10.55	11.12	50.00	-38.88	AVG
11	28.7860	7.66	12.02	19.68	60.00	-40.32	QP
12	29.8020	-2.82	12.16	9.34	50.00	-40.66	AVG



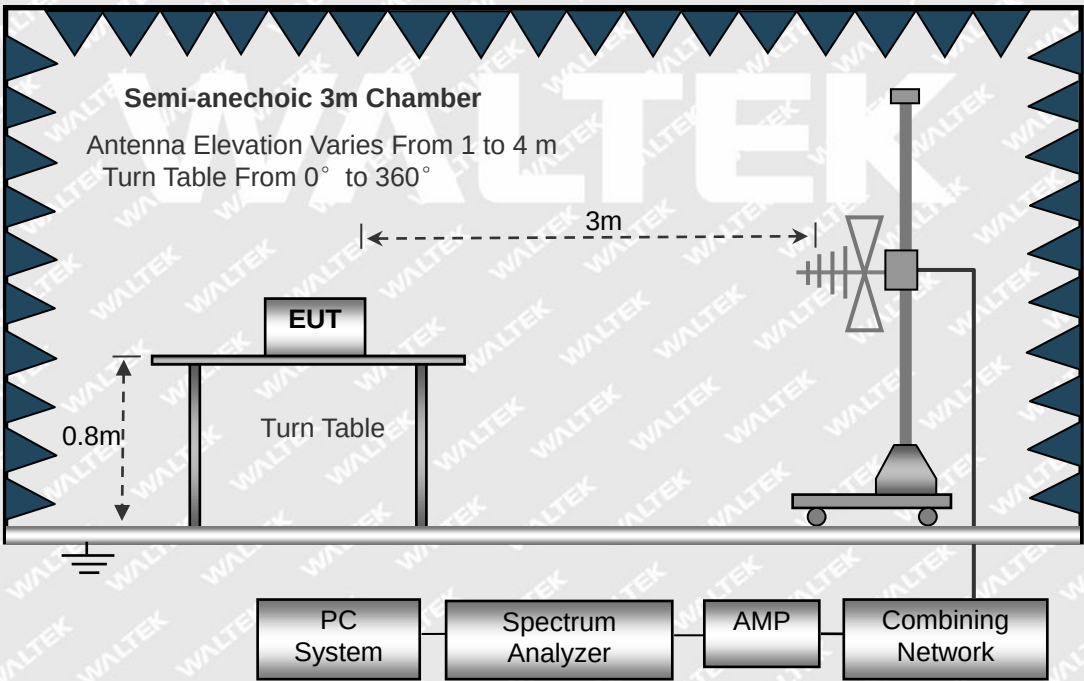
4. Radiated Emission

4.1 Measurement Uncertainty

Base on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any radiation emissions measurement:

Measurement uncertainty		
Parameter	Conditions	Uncertainty
Radiated Emissions	Radiated	30-200MHz $\pm 4.52\text{dB}$
		0.2-1GHz $\pm 5.56\text{dB}$
		1-6GHz $\pm 3.84\text{dB}$
		6-18GHz $\pm 3.92\text{dB}$

4.2 Basic Test Setup Block Diagram





4.3 Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and the Cable Factor, and subtracting the Amplifier Gain from the Amplitude reading. The basic equation is as follows:

$$\begin{aligned}\text{Corr. Ampl.} &= \text{Indicated Reading} + \text{Correct} \\ \text{Correct} &= \text{Ant. Factor} + \text{Cable Loss} - \text{Ampl. Gain}\end{aligned}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of -6dB μ V means the emission is 6dB μ V below the maximum limit for Class B device. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Corr. Ampl.} - \text{CISPR 11 Class B Limit}$$

4.4 Environmental Conditions

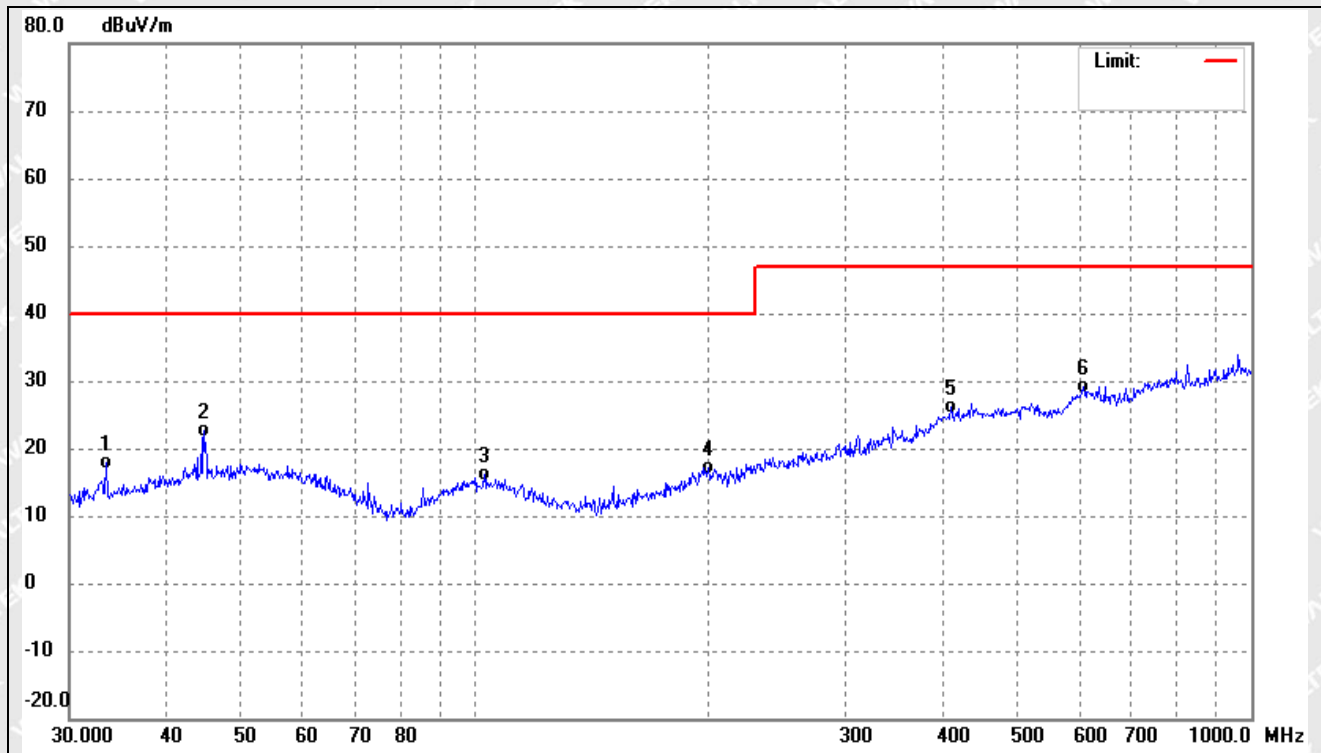
Temperature:	23.5 °C
Relative Humidity:	54 %
ATM Pressure:	998 mbar

4.5 Summary of Test Results

Please find the results below:



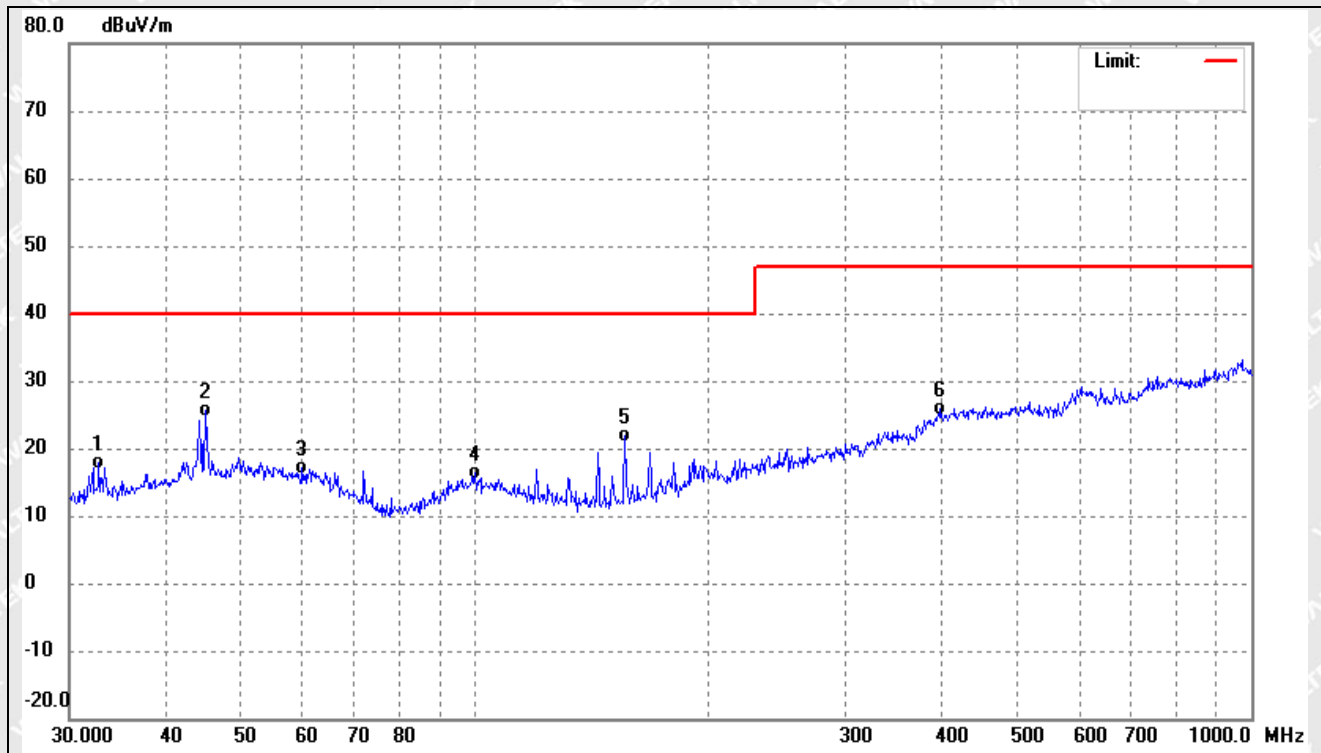
Test mode:	TM1	Polarity:	Horizontal
------------	-----	-----------	------------



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Remark
1	33.4449	31.09	-13.25	17.84	40.00	-22.16	QP
2	44.7433	32.90	-10.29	22.61	40.00	-17.39	QP
3	102.7192	27.77	-11.74	16.03	40.00	-23.97	QP
4	199.9856	27.29	-10.14	17.15	40.00	-22.85	QP
5	410.3825	28.23	-2.17	26.06	47.00	-20.94	QP
6	607.7867	28.53	0.55	29.08	47.00	-17.92	QP



Test mode:	TM1	Polarity:	Vertical
------------	-----	-----------	----------



No.	Frequency (MHz)	Reading (dBuV)	Correct (dB/m)	Result (dBuV/m)	Limit (dBuV/m)	Margin (dB)	Remark
1	32.7486	31.48	-13.48	18.00	40.00	-22.00	QP
2	44.9006	35.98	-10.26	25.72	40.00	-14.28	QP
3	59.8588	28.30	-11.13	17.17	40.00	-22.83	QP
4	99.8777	28.07	-11.81	16.26	40.00	-23.74	QP
5	155.9101	35.97	-14.08	21.89	40.00	-18.11	QP
6	397.6334	28.41	-2.50	25.91	47.00	-21.09	QP



5. Harmonic Current Emissions

5.1 Test Procedure

Test is conducted under the description of IEC 61000-3-2.

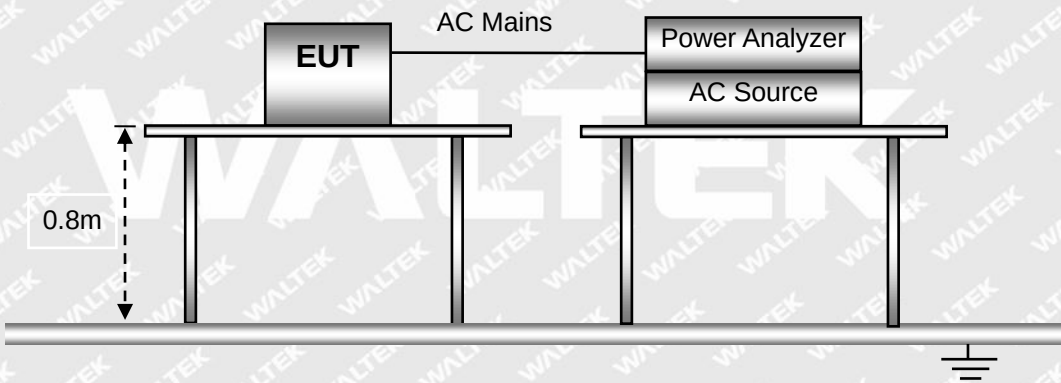
5.2 Test Standards

IEC 61000-3-2, Clause 7.2 Limits for Class A equipment.

5.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

5.4 Basic Test Setup Block Diagram



5.5 Harmonic Current Emissions Test Data

According to Clause 7 of IEC 61000-3-2, the rated power of the EUT is less than 75W, belong to 'equipment with a rated power of 75W or less', therefore 'limits are not specified in this edition of the standards'. It is deemed to fully fit the requirements of the standards.

Result: The EUT is compliance with the requirements of this section.



6. Voltage Fluctuation Flicker

6.1 Test Procedure

Test is conducted under the description of IEC 61000-3-3.

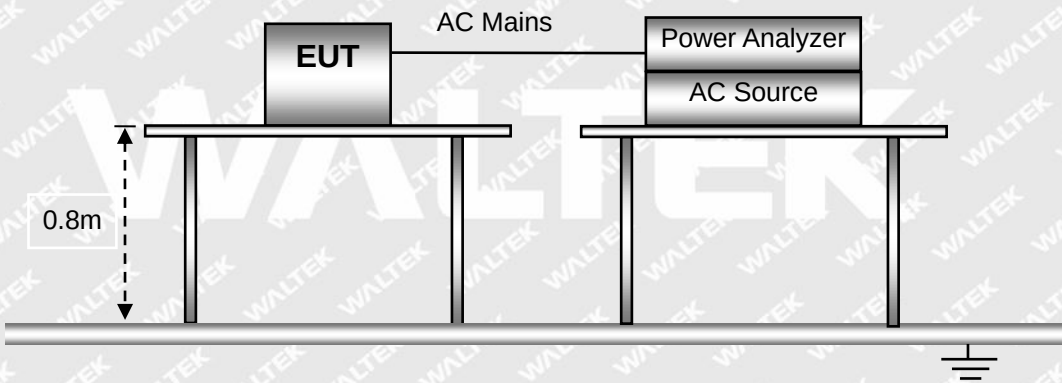
6.2 Test Standards

IEC 61000-3-3, Limit: Clause 5.

6.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

6.4 Basic Test Setup Block Diagram



6.5 Voltage Fluctuation and Flicker Test Data



Test mode:	TM1
------------	-----

Flicker Test Summary per IEC61000-3-3:2013+AMD2:2021 (Run time)

Comment: TM1

Customer: Customer

Test Result: Pass

Status: Test Completed

Pst and limit line

European Limits



Plt and limit line



Parameter values recorded during the test:

Vrms at the end of test (Volt): 229.93

Highest dt (%):

T-max (mS): 0

Highest dc (%): 0.00

Highest dmax (%): 0.00

Highest Pst (10 min. period): 0.242

Highest Plt (2 hr. period): 0.106

Test limit (%):

Test limit (mS): 500.0 Pass

Test limit (%): 3.30 Pass

Test limit (%): 4.00 Pass

Test limit: 1.000 Pass

Test limit: 0.650 Pass



7. Electrostatic Discharges (ESD)

7.1 Test Procedure

Test is conducted under the description of IEC 61000-4-2.

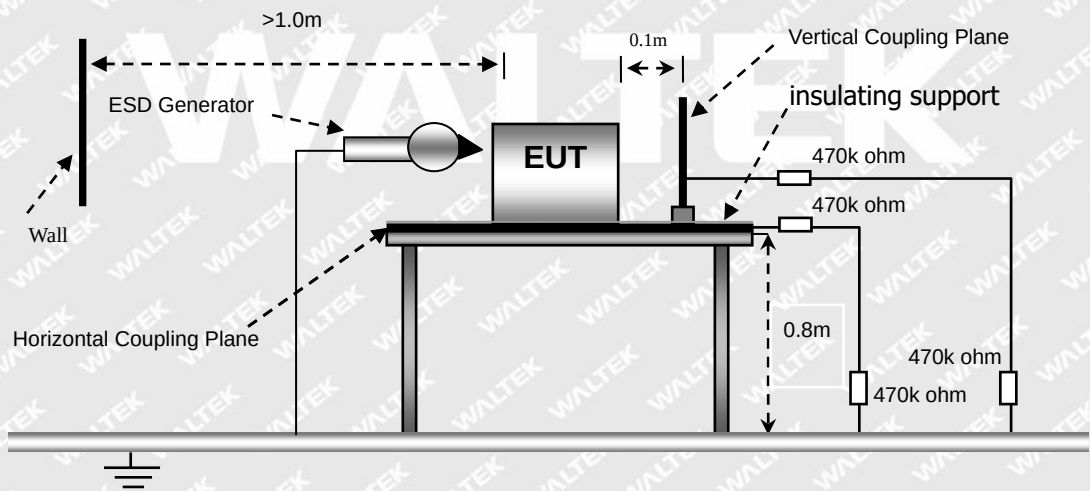
7.2 Test Performance

Performance Criterion: B

7.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

7.4 Basic Test Setup Block Diagram





7.5 Electrostatic Discharge Immunity Test Data

Table 1: Electrostatic Discharge Immunity (Air Discharge)

IEC 61000-4-2 Test Points	Test Voltage (kV)									
	-2	+2	-4	+4	-8	+8	-15	+15	-20	+20
Shell edge crack	A	A	A	A	A	A	A	A	/	/
DC Output port	A	A	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

IEC 61000-4-2 Test Points	Test Voltage (kV)									
	-2	+2	-4	+4	-8	+8	-15	+15	-20	+20
Screw	A	A	A	A	A	A	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP & VCP)

IEC 61000-4-2 Test Points	Test Voltage (kV)									
	-2	+2	-4	+4	-8	+8	-10	+10	-15	+15
HCP (6 Sides)	A	A	A	A	A	A			/	/
VCP (4 Sides)	A	A	A	A	A	A			/	/

Test Result: Pass



8. Continuous RF Electromagnetic Field Disturbances (RS)

8.1 Test Procedure

Test is conducted under the description of IEC 61000-4-3.

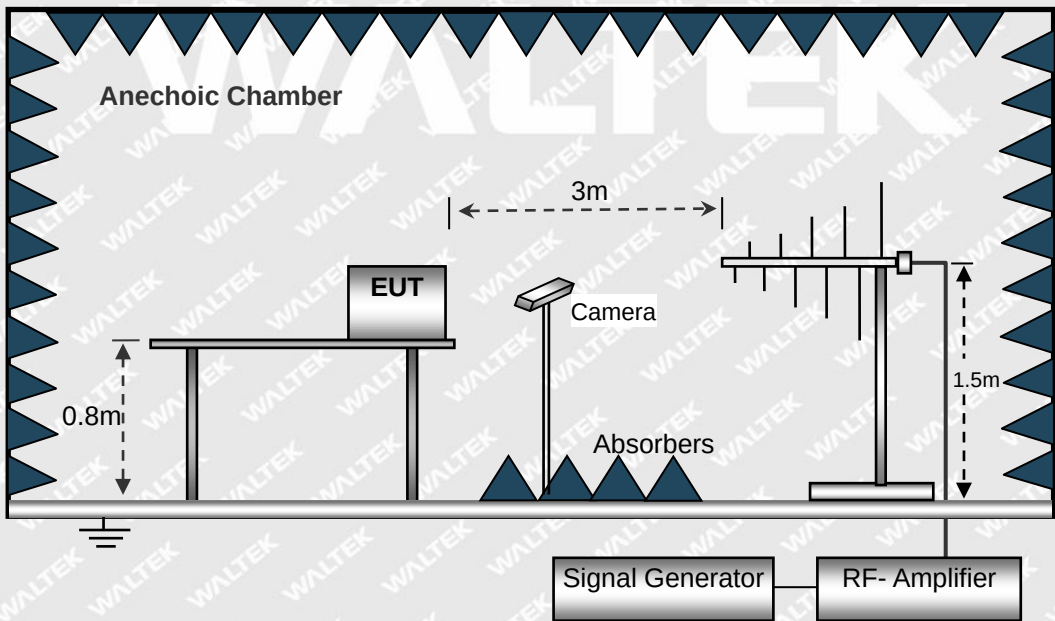
8.2 Test Performance

Performance Criterion: A

8.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

8.4 Basic Test Setup Block Diagram





8.5 Continuous Radiated Disturbances Test Data

Frequency step: 1% of fundamental
Dwell time: 1 second
Modulation: AM by 1kHz sine wave with 80% modulation depth

Frequency Range(MHz)	Field (V/m)	Front		Rear		Left Side		Right Side	
		VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-2700	10	A	A	A	A	A	A	A	A

Test Result: Pass

WALTEK



9. Electrical Fast Transients (EFT)

9.1 Test Procedure

Test is conducted under the description of IEC 61000-4-4.

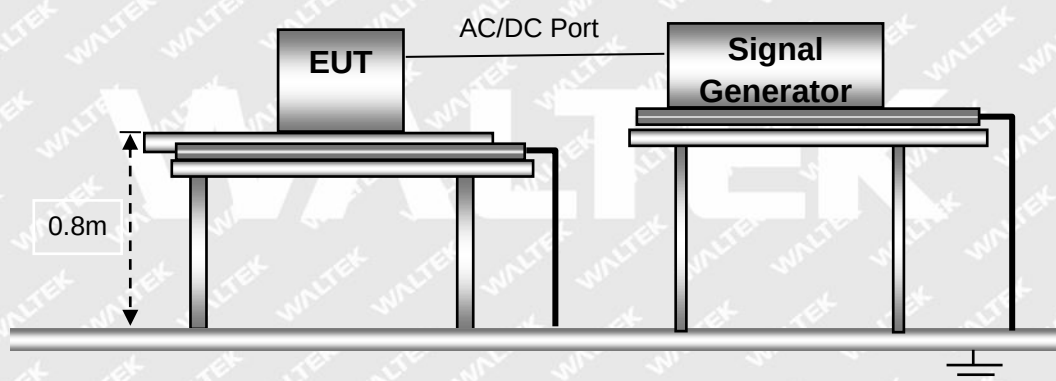
9.2 Test Performance

Performance Criterion: B

9.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

9.4 Basic Test Setup Block Diagram





9.5 Electrical Fast Transients Test Data

Repetition frequency 100 kHz

IEC 61000-4-4 Test Points		Test Voltage (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
Power Supply Power Port of EUT	L	/	/	/	/	A	A	/	/
	N	/	/	/	/	A	A	/	/
	PE	/	/	/	/	/	/	/	/
	L+N	/	/	/	/	A	A	/	/
	L+PE	/	/	/	/	/	/	/	/
	N+PE	/	/	/	/	/	/	/	/
	L+N+PE	/	/	/	/	/	/	/	/
Signal ports	RJ45	/	/	/	/	/	/	/	/

Test Result: Pass

WALTEK



10. Surges

10.1 Test Procedure

Test is conducted under the description of IEC 61000-4-5.

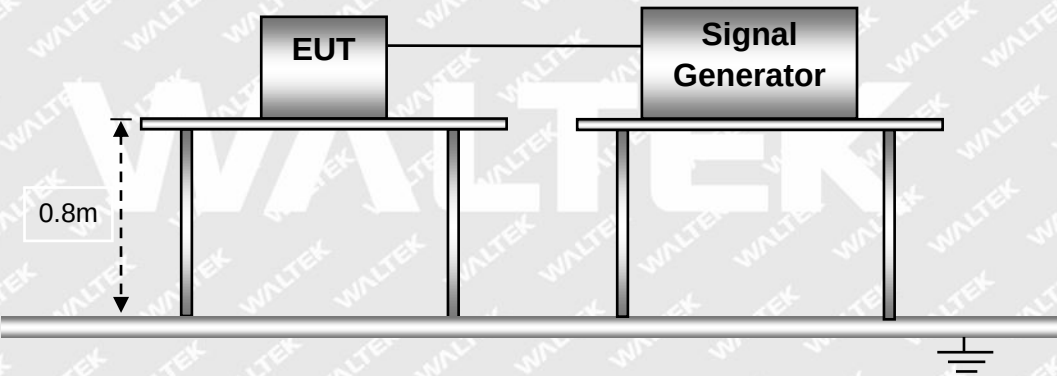
10.2 Test Performance

Performance Criterion: B

10.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

10.4 Basic Test Setup Block Diagram





10.5 Surge Test Data

Test Voltage (kV)	Poll	Path	Pass	Fail
0.5kV	±	L-N	A	/
1kV	±	L-N	A	/
2kV	±	L-N, L-PE, N-PE	/	/
4kV	±	L-PE, N-PE	/	/

Test Result: Pass

WALTEK



11. Continuous Induced RF Disturbances (C/S)

11.1 Test Procedure

Test is conducted under the description of IEC 61000-4-6.

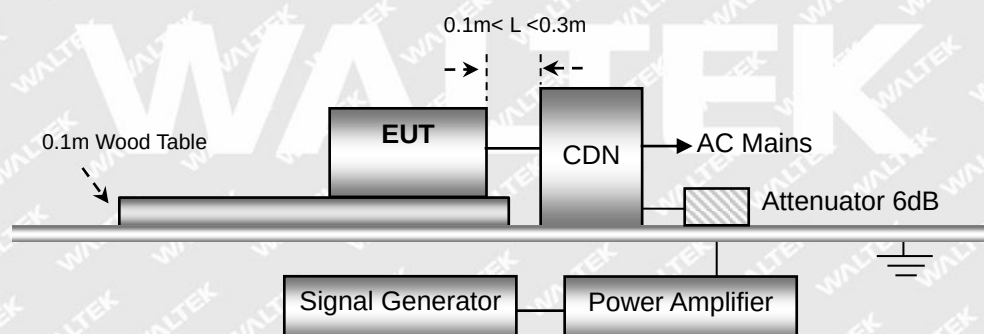
11.2 Test Performance

Performance Criterion: A

11.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

11.4 Basic Test Setup Block Diagram





11.5 Continuous Conducted Disturbances Test Data

Sweep frequency range: 0.15 MHz to 80 MHz
Frequency step: 1% of fundamental
Dwell time: 1 second

AC Port

Frequency MHz	Injected Position	Voltage level (e.m.f.)	Observations (Performance Criterion)	Result
0.15-80	AC Mains	1V	/	Pass
0.15-80	AC Mains	3V	A	Pass
0.15-80	AC Mains	10V	/	Pass

Test Result: Pass

WALTEK



12. Power-Frequency Magnetic Fields (PFMF)

12.1 Test Procedure

Test is conducted under the description of IEC 61000-4-8.

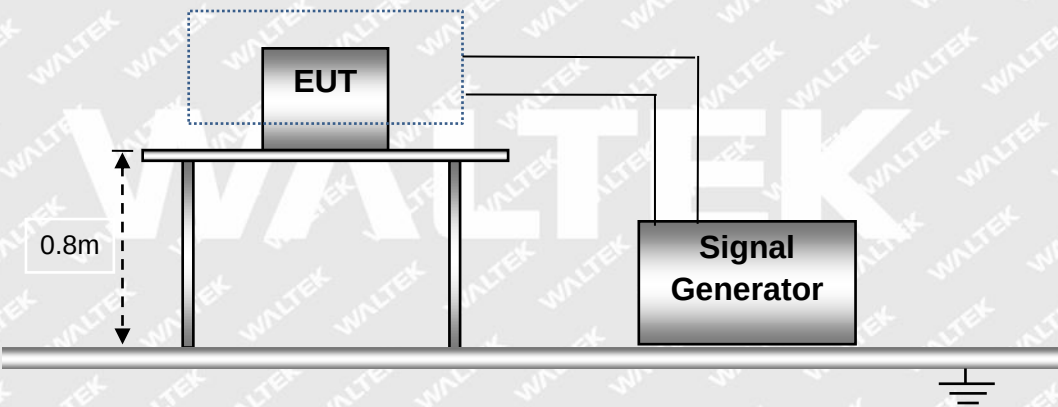
12.2 Test Performance

Performance Criterion: A

12.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

12.4 Basic Test Setup Block Diagram



12.5 Power-Frequency Magnetic Field Test Data

Level	Magnetic Field Strength (r.m.s) A/m	Frequency Hz	Induction Coil Postion	Pass	Fail
1	1	50/60	X, Y, Z	/	/
2	3	50/60	X, Y, Z	/	/
3	10	50/60	X, Y, Z	/	/
4	30	50/60	X, Y, Z	A	/

Test Result: Pass



13. Voltage Dips and Interruptions

13.1 Test Procedure

Test is conducted under the description of IEC 61000-4-11.

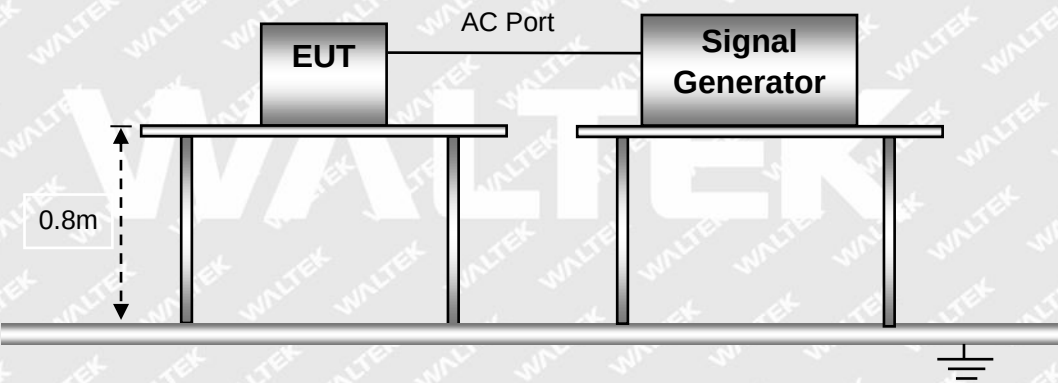
13.2 Test Performance

Performance Criterion: B/C

13.3 Environmental Conditions

Temperature:	23.5 °C
Relative Humidity:	53 %
ATM Pressure:	998 mbar

13.4 Basic Test Setup Block Diagram





13.5 Voltage Dips And Interruptions Test Data

U: Vlotage dips in % U_T (U_T is rated voltage for the EUT)

T: Test duration

Level	U	T	Phase Angle	N	Pass	Fail
1	100%	10ms	0°/45°/90°/135°/180°,225°/270°/315°	3	A	/
2	100%	20ms	0°/45°/90°/135°/180°,225°/270°/315°	3	A	/
3	70%	500ms	0°/45°/90°/135°/180°,225°/270°/315°	3	B	/
4	100%	5000ms	0°/45°/90°/135°/180°,225°/270°/315°	3	B	/

Test Result: Pass

WALTEK



EXHIBIT 1 - PRODUCT LABELING

Proposed CE Label Format

MEDICAL AC/DC ADAPTOR

Model: GTM3T41-12-150R-3

Brand: 

Importer Name: XXX

Importer Address: XXX

1. GlobTek, Inc.

2. GlobTek (Suzhou) Co., Ltd

1.186 Veterans Dr. Northvale. NJ07647 USA

2. Building 4, No.76, Jin Ling East Rd., Suzhou
Industrial Park, Suzhou, JiangSu 215021, China

Specifications: Text is Black in color and is justified. Labels are printed in indelible ink on permanent adhesive backing or silk-screened onto the EUT or shall be affixed at a conspicuous location on the EUT. The 'CE' marking must be affixed to the EUT or to its data plate. Where this is not possible or not warranted on account of the nature of the apparatus, it must be affixed to the packaging, if any, and to the accompanying documents. The 'CE' marking must have a height of at least 5 mm. If the 'CE' marking is reduced or enlarged the proportions given in the above graduated drawing must be respected. The Importer name, address and Manufacturer name and address should indicate on marking label or packaging or in a document accompanying.

Proposed Label Location on EUT

Label Location





EXHIBIT 2 - EUT PHOTOGRAPHS

EUT View 1



EUT View 2





Reference No.: WTX24X07174094E

EUT View 3



EUT View 4





Reference No.: WTX24X07174094E

EUT View 5



EUT View 6

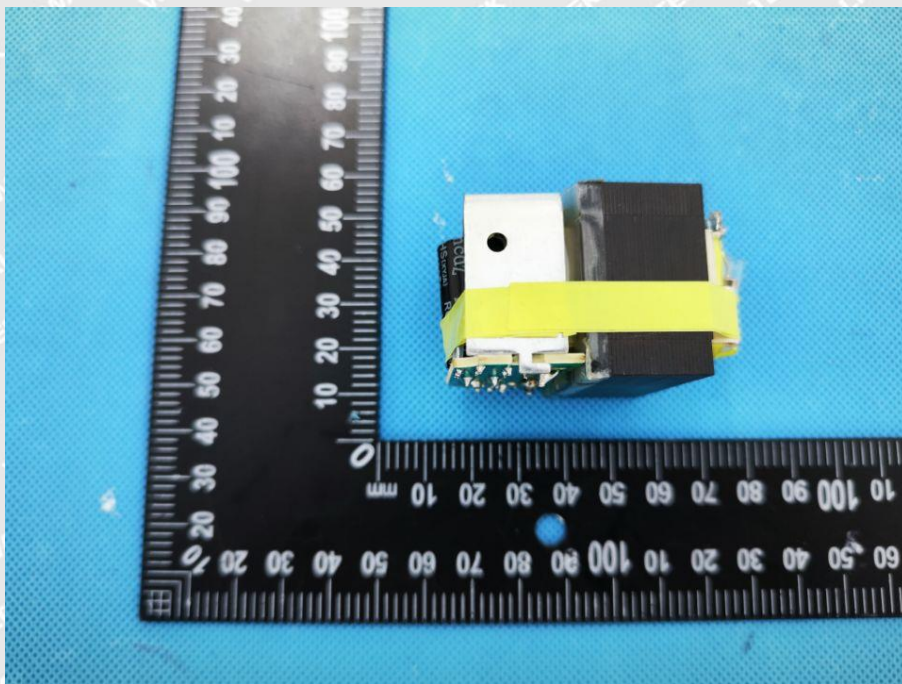




EUT Housing and Board View 1



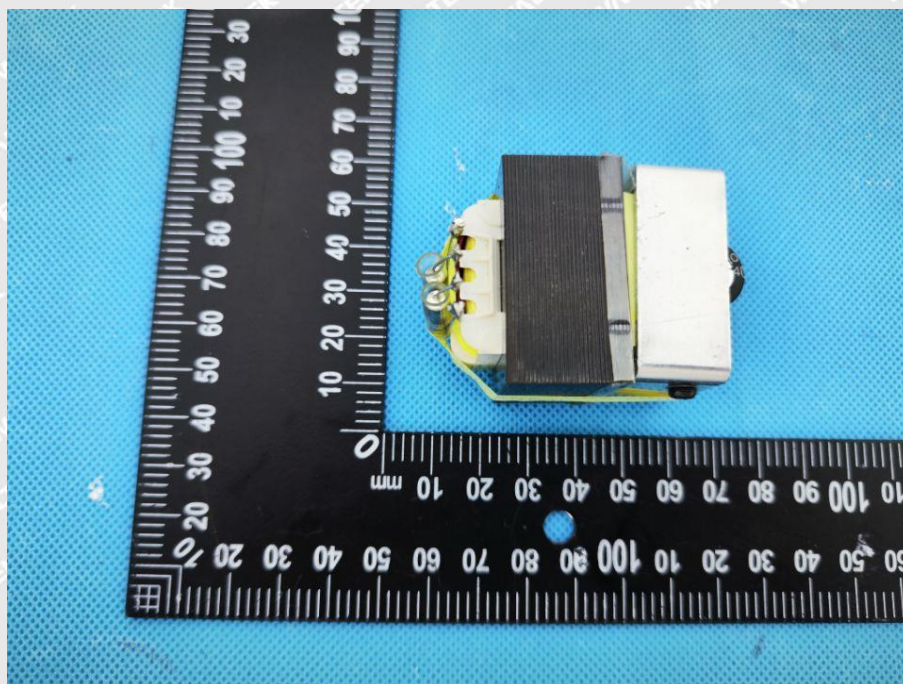
Solder Board-Component View 2



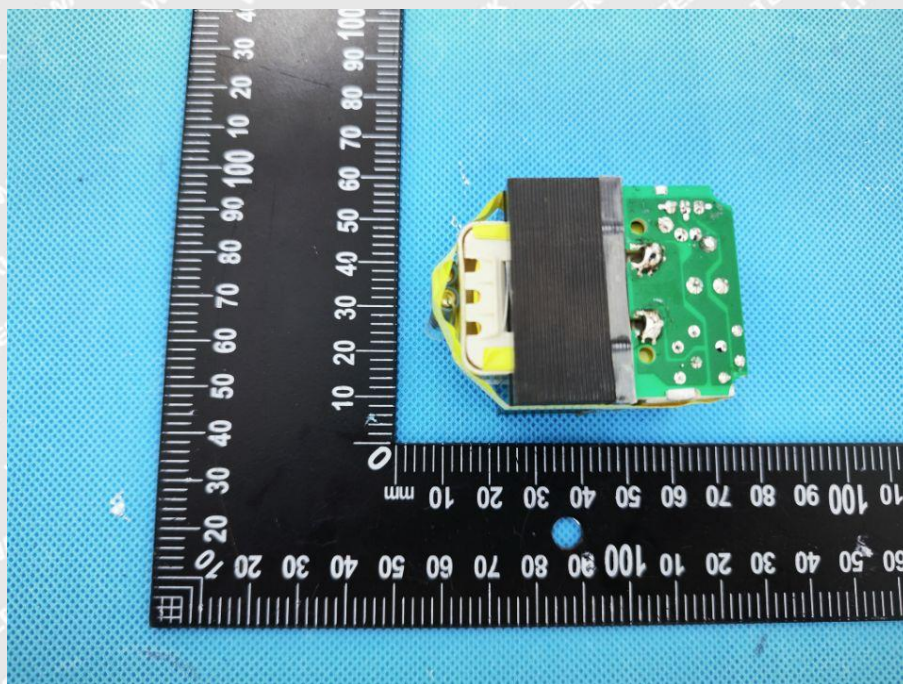


Reference No.: WTX24X07174094E

Solder Board-Component View 3



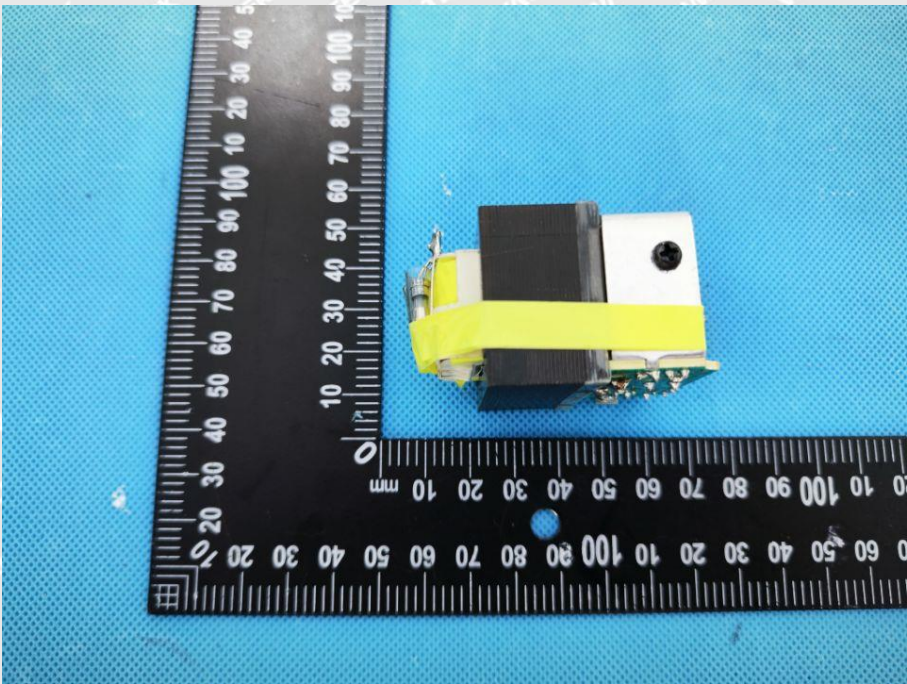
Solder Board-Component View 4



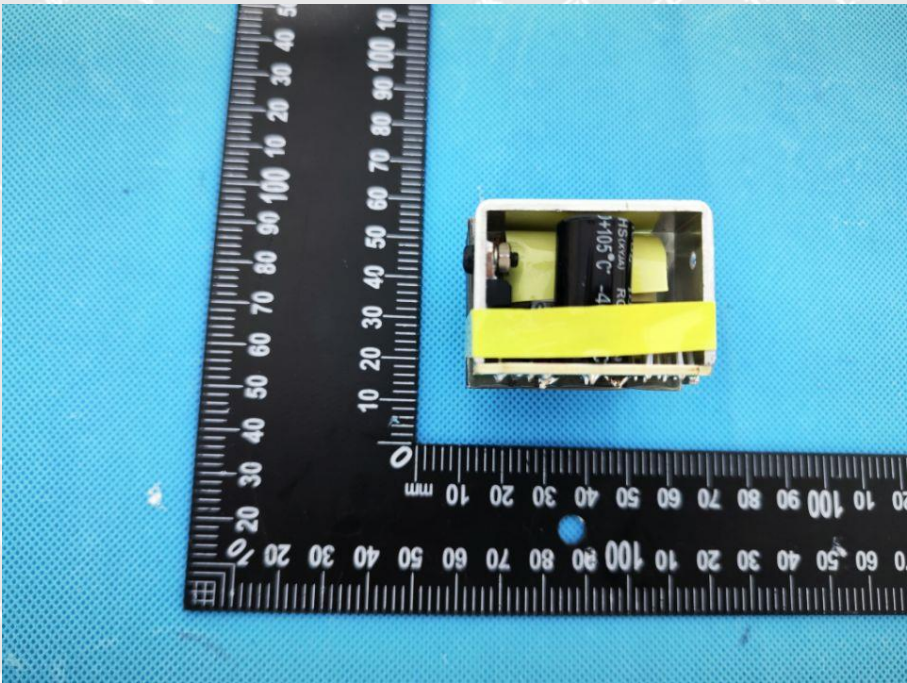


Reference No.: WTX24X07174094E

Solder Board-Component View 5



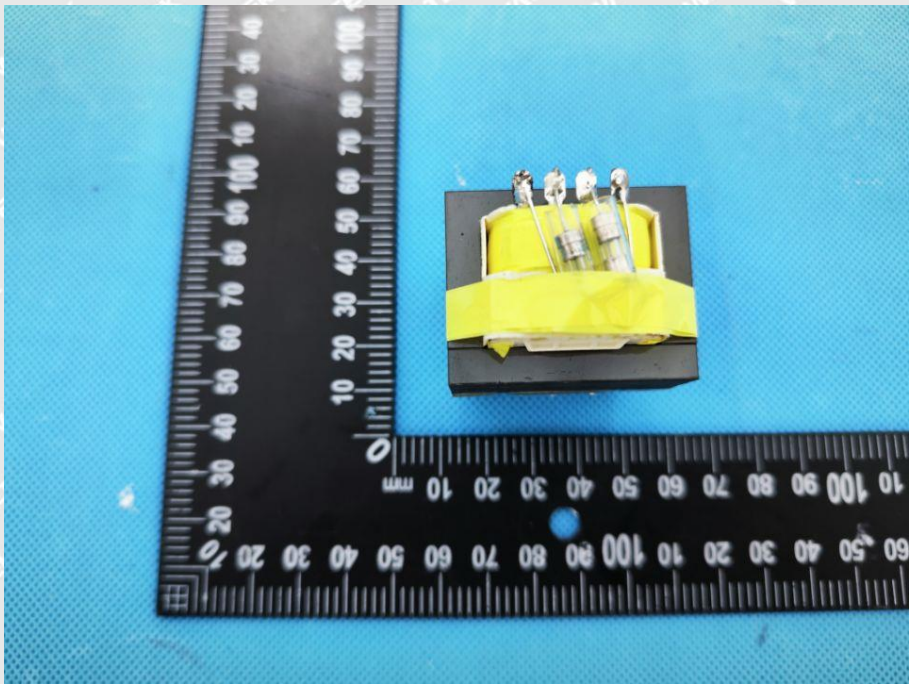
Solder Board-Component View 6





Reference No.: WTX24X07174094E

Solder Board-Component View 7



WALTEK

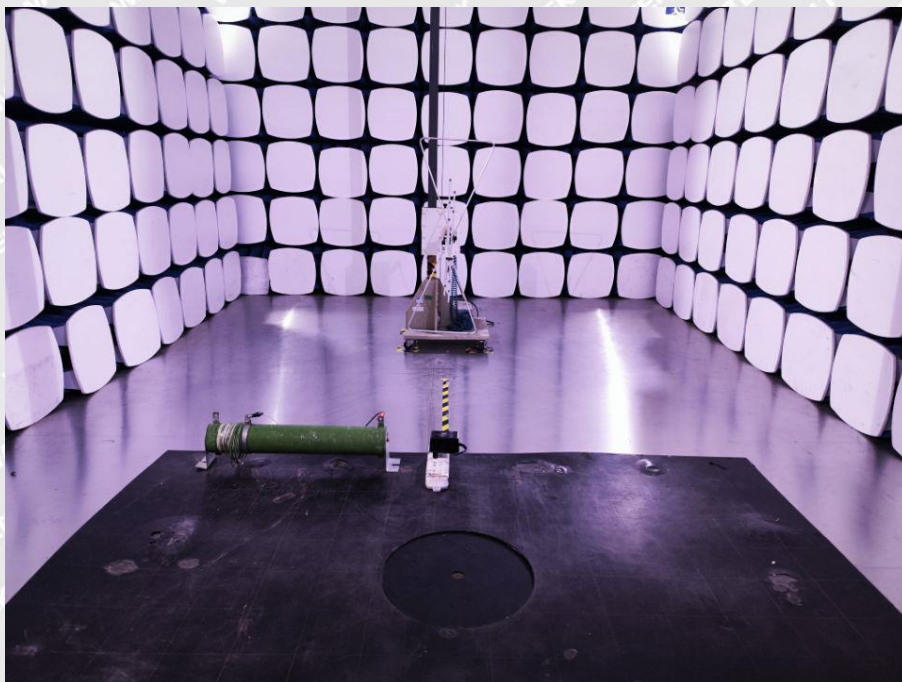


EXHIBIT 3 - TEST SETUP PHOTOGRAPHS

Conduction Emission Test View



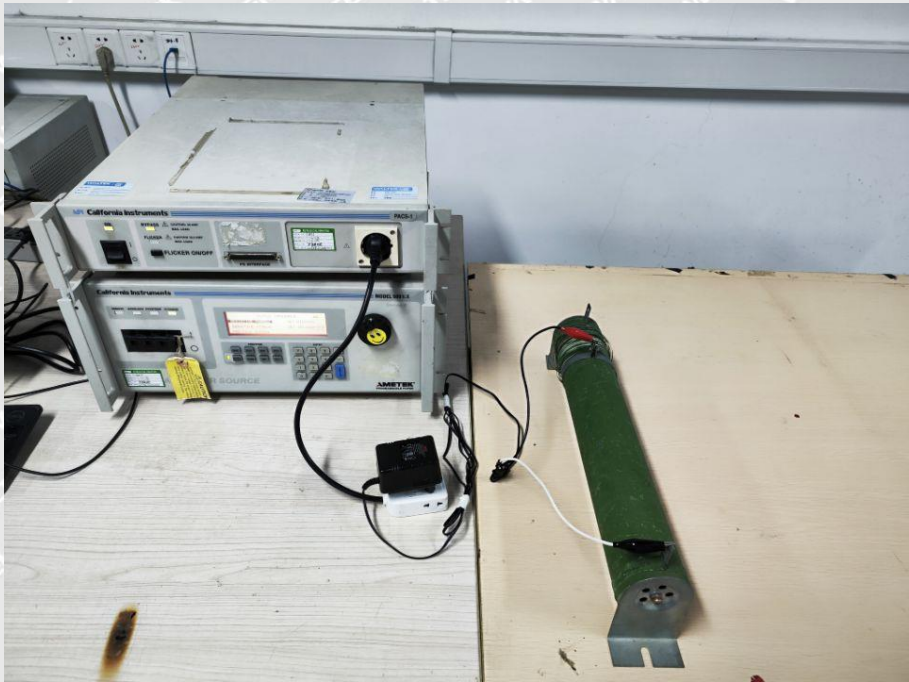
Radiation Emission Test View





Reference No.: WTX24X07174094E

Harmonic/Flicker Test View



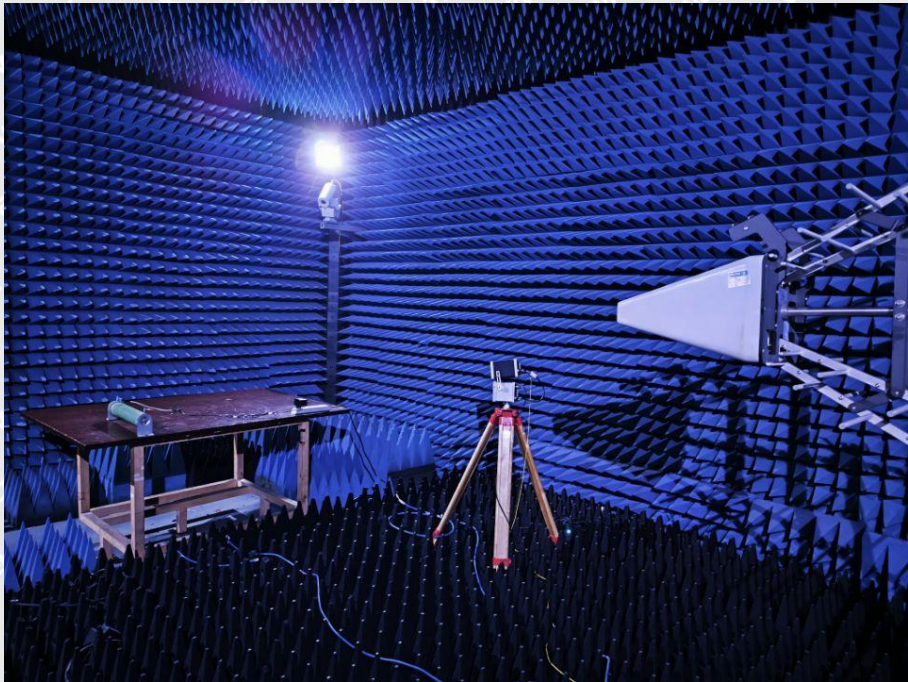
IEC 61000-4-2 Test View





Reference No.: WTX24X07174094E

IEC 61000-4-3 Test View



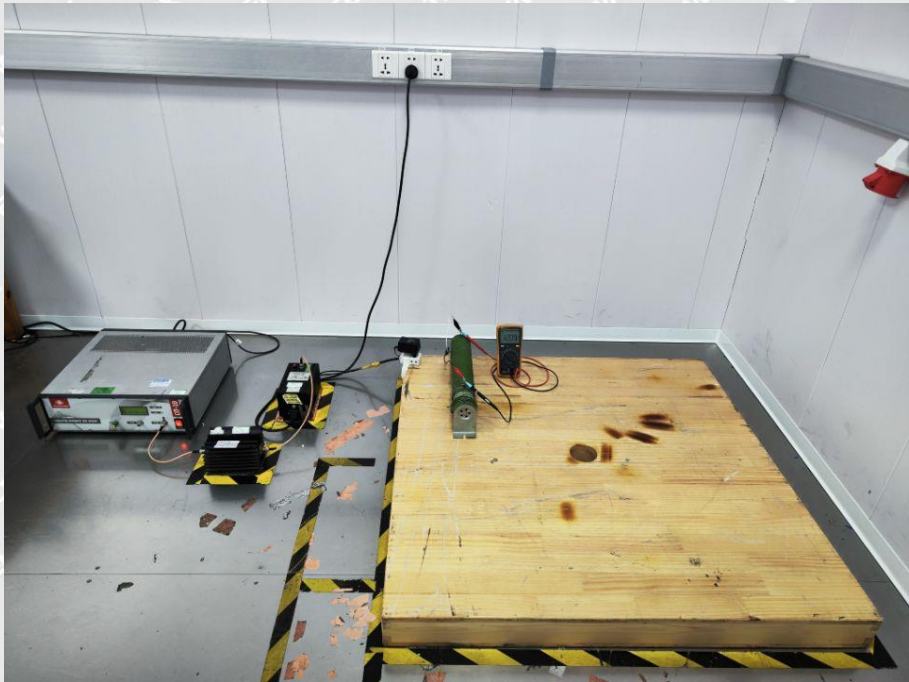
IEC 61000-4-4/5/11 Test View



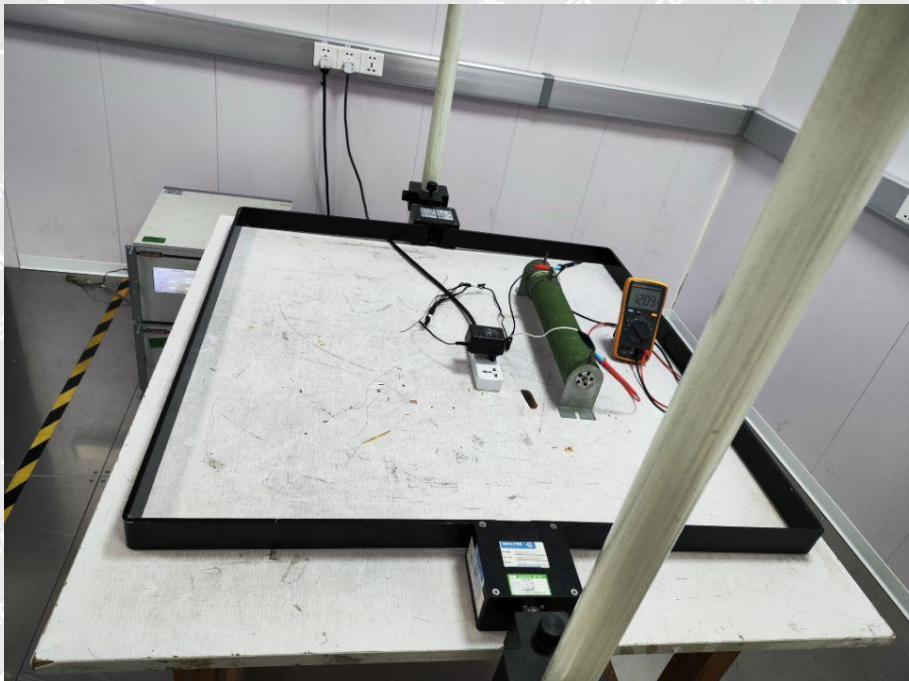


Reference No.: WTX24X07174094E

IEC 61000-4-6 Test View



IEC 61000-4-8 Test View



***** END OF REPORT *****